

- ★ 100% EAS Guaranteed
- ★ Green Device Available
- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology

### Product Summary



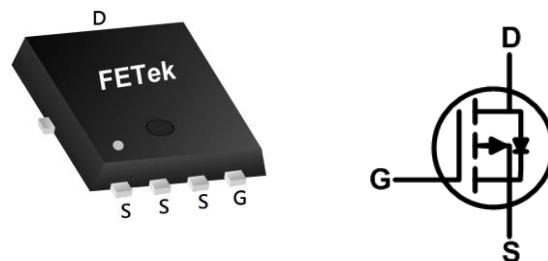
BVDSS	RDS(ON)	ID
-100V	50mΩ	-8A

### Description

The FKBA0139 uses advanced trench MOSFET technology to provide excellent  $R_{DS(ON)}$  and gate charge for use in a wide variety of other applications.

The FKBA0139 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

### PRPAK5X6 Pin Configuration



### Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	-100	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D @ T_A=25^\circ C$	Continuous Drain Current, $V_{GS} @ -10V^1$	-8	A
$I_D @ T_A=100^\circ C$	Continuous Drain Current, $V_{GS} @ -10V^1$	-6.5	A
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	-45	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	345	mJ
$I_{AS}$	Avalanche Current	28	A
$P_D @ T_A=25^\circ C$	Total Power Dissipation <sup>4</sup>	5.5	W
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

### Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	---	62	°C/W
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup> $t \leq 10s$	---	22	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	---	1.22	°C/W

### Electrical Characteristics ( $T_J=25^\circ\text{C}$ , unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$ , $I_D=-250\mu\text{A}$	-100	---	---	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=-10\text{V}$ , $I_D=-8\text{A}$	---	42	50	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}$ , $I_D=-6\text{A}$	---	46	55	
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{GS}}=V_{\text{DS}}$ , $I_D=-250\mu\text{A}$	-1.2	-1.8	-2.5	V
$I_{\text{DSS}}$	Drain-Source Leakage Current	$V_{\text{DS}}=-100\text{V}$ , $V_{\text{GS}}=0\text{V}$ , $T_J=25^\circ\text{C}$	---	---	-1	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Source Leakage Current	$V_{\text{GS}}=\pm20\text{V}$ , $V_{\text{DS}}=0\text{V}$	---	---	$\pm100$	$\text{nA}$
$g_{\text{fs}}$	Forward Transconductance	$V_{\text{DS}}=-10\text{V}$ , $I_D=-10\text{A}$	---	32	---	S
$Q_g$	Total Gate Charge	$V_{\text{DS}}=-80\text{V}$ , $V_{\text{GS}}=-10\text{V}$ , $I_D=-8\text{A}$	---	92	---	$\text{nC}$
$Q_{\text{gs}}$	Gate-Source Charge		---	17.5	---	
$Q_{\text{gd}}$	Gate-Drain Charge		---	14	---	
$T_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}}=-50\text{V}$ , $V_{\text{GS}}=-10\text{V}$ , $R_G=3.3\Omega$ , $I_D=-1\text{A}$	---	20.5	---	$\text{ns}$
$T_r$	Rise Time		---	32.2	---	
$T_{\text{d(off)}}$	Turn-Off Delay Time		---	123	---	
$T_f$	Fall Time		---	63.7	---	
$C_{\text{iss}}$	Input Capacitance	$V_{\text{DS}}=-25\text{V}$ , $V_{\text{GS}}=0\text{V}$ , $f=1\text{MHz}$	---	6516	---	$\text{pF}$
$C_{\text{oss}}$	Output Capacitance		---	223	---	
$C_{\text{rss}}$	Reverse Transfer Capacitance		---	125	---	

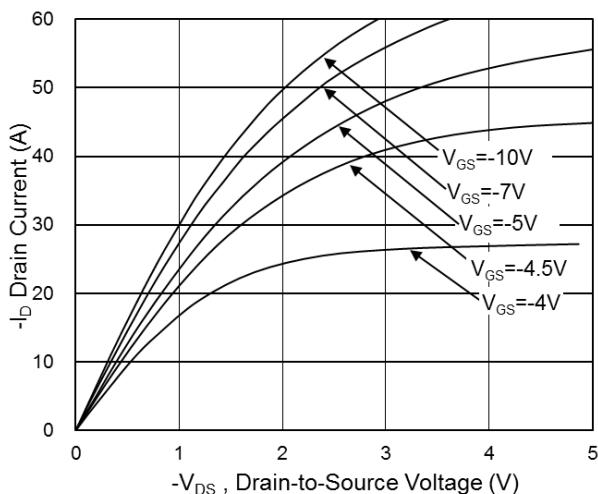
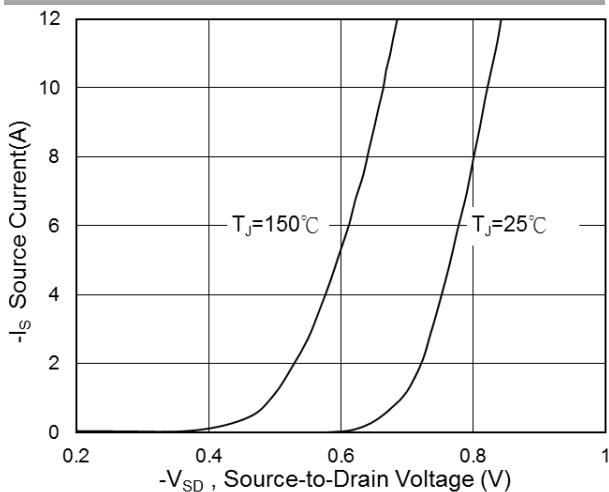
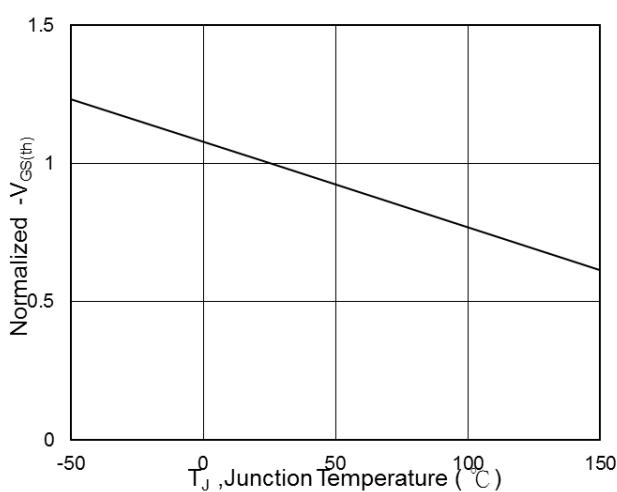
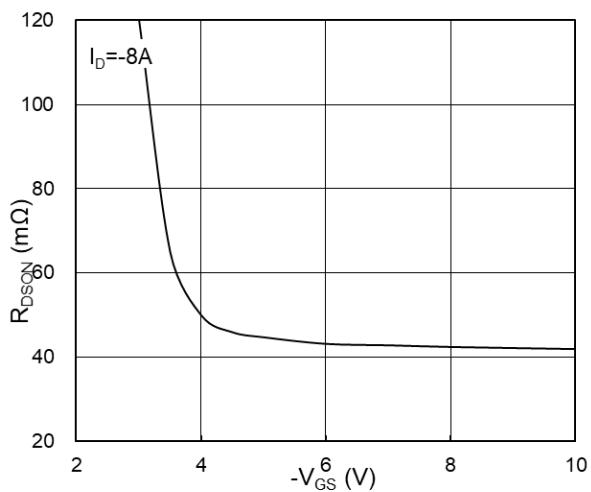
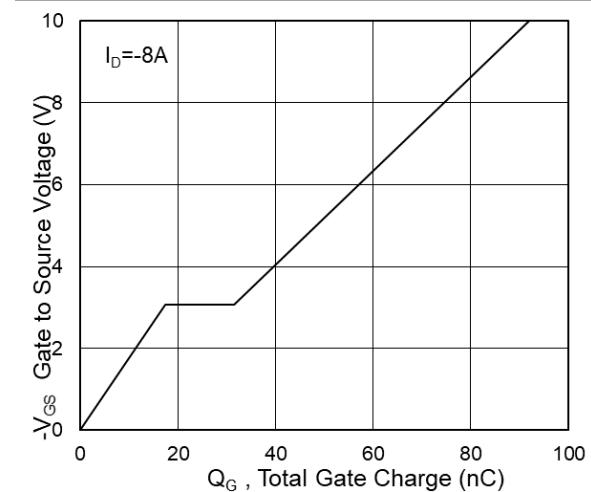
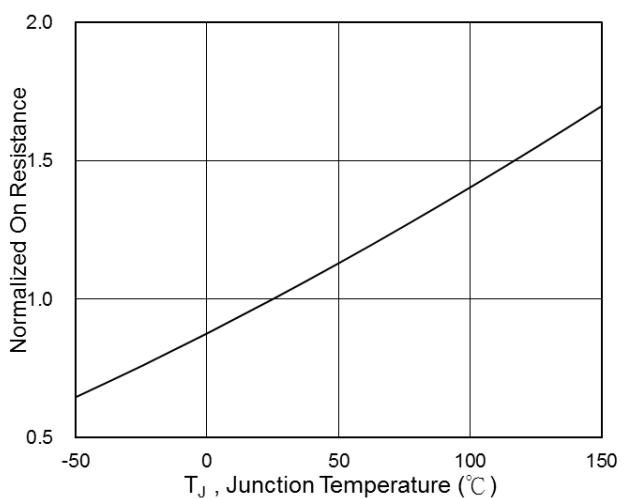
### Diode Characteristics

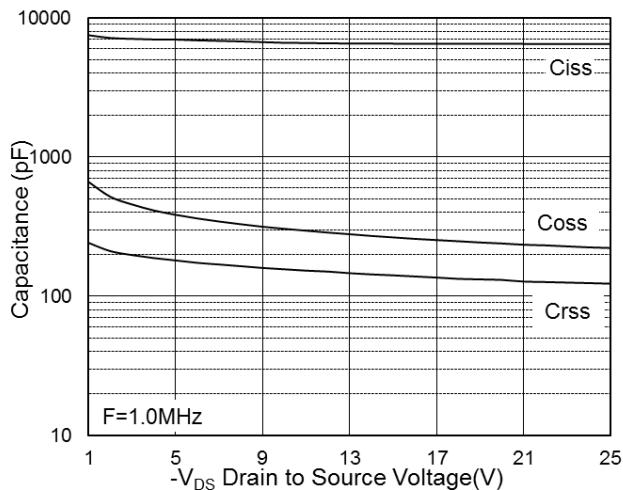
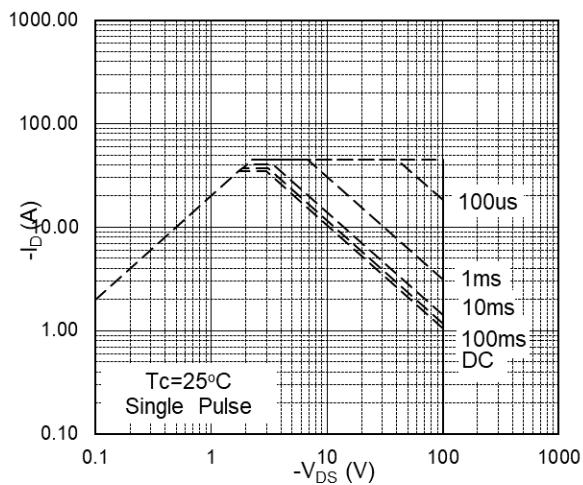
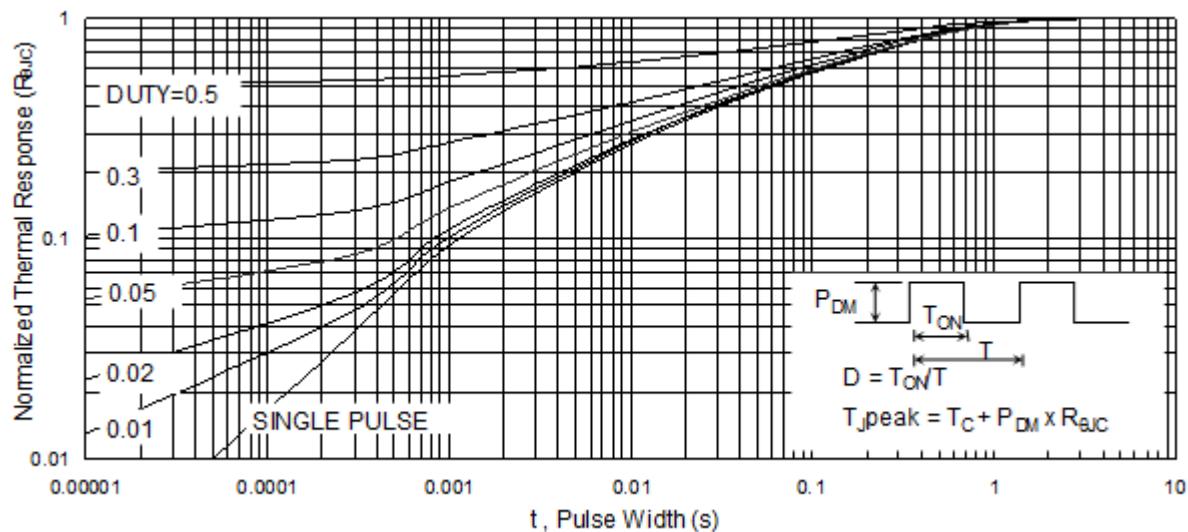
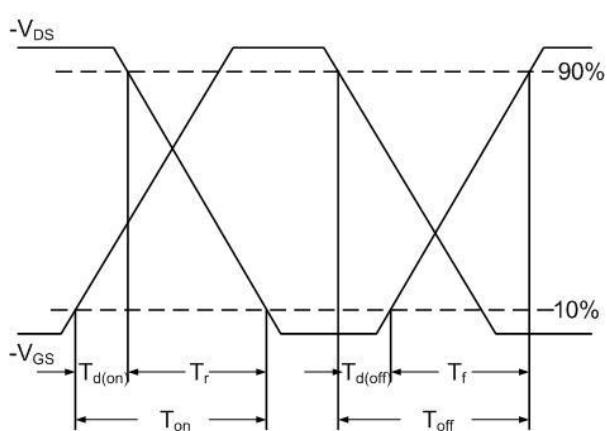
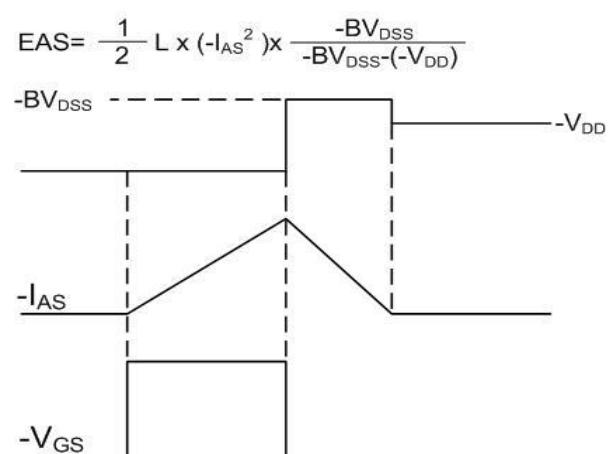
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$I_s$	Continuous Source Current <sup>1,5</sup>	$V_G=V_D=0\text{V}$ , Force Current	---	---	-30	A
$V_{\text{SD}}$	Diode Forward Voltage <sup>2</sup>	$V_{\text{GS}}=0\text{V}$ , $I_s=-1\text{A}$ , $T_J=25^\circ\text{C}$	---	---	1.2	V
$t_{\text{rr}}$	Reverse Recovery Time	$I_F=-14\text{A}$ , $dI/dt=-100\text{A}/\mu\text{s}$ , $T_J=25^\circ\text{C}$	---	31.2	---	nS
	Reverse Recovery Charge		---	31.97	---	nC

Note :

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq 300\mu\text{s}$  , duty cycle  $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is  $V_{\text{DD}}=-25\text{V}$ , $V_{\text{GS}}=-10\text{V}$ , $L=0.88\text{mH}$ , $I_{\text{AS}}=-28\text{A}$
- 4.The power dissipation is limited by  $150^\circ\text{C}$  junction temperature
- 5.The data is theoretically the same as  $I_b$  and  $I_{\text{DM}}$  , in real applications , should be limited by total power dissipation.

### Typical Characteristics


**Fig.1 Typical Output Characteristics**

**Fig.3 Typical S-D Diode Forward Voltage**

**Fig.5 Normalized  $V_{GS(th)}$  vs  $T_J$** 

**Fig.2 On-Resistance vs G-S Voltage**

**Fig.4 Gate-Charge Characteristics**

**Fig.6 Normalized  $R_{DS(on)}$  vs  $T_J$**


**Fig.7 Capacitance**

**Fig.8 Safe Operating Area**

**Fig.9 Normalized Maximum Transient Thermal Impedance**

**Fig.10 Switching Time Waveform**

**Fig.11 Unclamped Inductive Waveform**